EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	349	702/81.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/21 08:32
L2	186	702/82.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/21 08:32
L3	115	702/83.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/21 08:33
L4	422	702/84.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/21 08:33
L6	151176	(production or manufactur$3 or fabrication) and (semiconductor or semi adj conductor or wafer$1) and (plurality or group) with (machine$1 or apparatus or instrument$1 or equipment$1 or press or device$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/21 08:35
L7	62	1 and 6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/21 08:35
L8	26	2 and 6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/21 08:35
L9	33	3 and 6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/21 08:36
L10	88	4 and 6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/21 08:36

L11	25	(manufactur$3 or fabrication) same (detect$3 or determin$3 or identif$4 or measur$3 or judg$5 or analy$4 or diagnos$3) with (degrad$3 or abnormal$5 or performance or yield$1 or (production or defect$3 or fail$3) near4 rate$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin$4 or equipments or instruments)	US-PGPUB	OR	ON	2006/02/21 08:36
L12	44	1 and "25"	US-PGPUB	OR	ON	2006/02/21 08:36
L13	13	2 and "25"	US-PGPUB	OR	ON	2006/02/21 08:37
L14	0	1 and 11	US-PGPUB	OR	ON	2006/02/21 08:37
L15	0	2 and 11	US-PGPUB	OR	ON	2006/02/21 08:37
L16	0	3 and 11	US-PGPUB	OR	ON	2006/02/21 08:37
L17	1	4 and 11	US-PGPUB	OR	ON	2006/02/21 08:37